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PATENT
1505-1089

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Anna IMBERG

Application No. 10/560,165

Filed December 9, 2005

COMPOSITE MATERIALS AND PARTICLES

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 9, 2006

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying document, a copy of which is attached to this statement, is made of record on the enclosed Form PTO-1449.

A concise explanation of the relevance of this item is that this reference was cited by the International Bureau in the corresponding International Application Serial No. PCT/SE2004/000917, filed June 10, 2004.

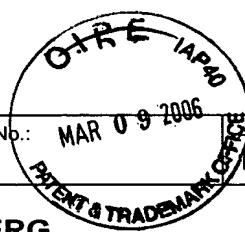
Respectfully submitted,

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A handwritten signature in black ink, appearing to read "ROBERT J. PATCH".

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION <small>(Use several sheets if necessary)</small>			Attorney Docket No.: 1505-1089 <i>MAR 09 2005</i> Application No.: 10/560,165 <i>PATENT & TRADEMARK OFFICE</i>				
			Applicant: Anna IMBERG				
			Filing Date: December 9, 2005		Group Art Unit:		
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass		
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
	JP 6-95082	04/08/1994	JAPAN (English abstract and claims)			<input type="checkbox"/> Yes	<input type="checkbox"/> No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER:			DATE CONSIDERED				

EXAMINER: _____ DATE CONSIDERED _____

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience